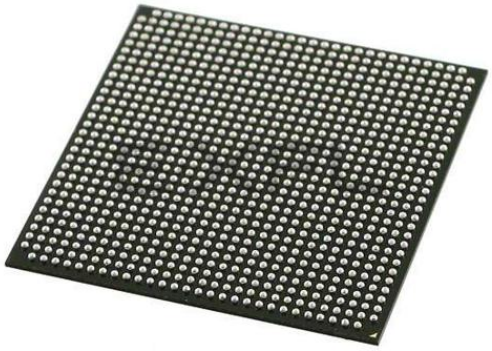

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	7362
Number of Logic Elements/Cells	156000
Total RAM Bits	11746304
Number of I/O	416
Number of Gates	-
Voltage - Supply	1.07V ~ 1.13V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	896-BBGA, FCBGA
Supplier Device Package	896-FBGA (31x31)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5agxma3d4f31i5

Contents

Symbol	Description	Condition	Minimum(1)	Typical	Maximum(1)	Unit
V_{CCIO}	I/O buffers power supply	3.3 V	3.135	3.3	3.465	V
		3.0 V	2.85	3.0	3.15	V
		2.5 V	2.375	2.5	2.625	V
		1.8 V	1.71	1.8	1.89	V
		1.5 V	1.425	1.5	1.575	V
		1.35 V	1.283	1.35	1.418	V
		1.25 V	1.19	1.25	1.31	V
		1.2 V	1.14	1.2	1.26	V
V_{CCD_FPLL}	PLL digital voltage regulator power supply	—	1.425	1.5	1.575	V
V_{CCA_FPLL}	PLL analog voltage regulator power supply	—	2.375	2.5	2.625	V
V_I	DC input voltage	—	–0.5	—	3.6	V
V_O	Output voltage	—	0	—	V_{CCIO}	V
T_J	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	–40	—	100	°C
t_{RAMP}(4)	Power supply ramp time	Standard POR	200 µs	—	100 ms	—
		Fast POR	200 µs	—	4 ms	—

(1) The power supply value describes the budget for the DC (static) power supply tolerance and does not include the dynamic tolerance requirements. Refer to the PDN tool for the additional budget for the dynamic tolerance requirements.

(4) This is also applicable to HPS power supply. For HPS power supply, refer to t_{RAMP} specifications for standard POR when `HPS_PORSEL` = 0 and t_{RAMP} specifications for fast POR when `HPS_PORSEL` = 1.

Symbol	Description	Condition (V)	Calibration Accuracy			Unit
			–I3, –C4	–I5, –C5	–C6	
60-Ω and 120-Ω R_T	Internal parallel termination with calibration (60-Ω and 120-Ω setting)	V_{CCIO} = 1.2	–10 to +40	–10 to +40	–10 to +40	%
25-Ω $R_{S\_left\_shift}$	Internal left shift series termination with calibration (25-Ω $R_{S\_left\_shift}$ setting)	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	±15	±15	±15	%

OCT Without Calibration Resistance Tolerance Specifications

Table 1-9: OCT Without Calibration Resistance Tolerance Specifications for Arria V Devices

This table lists the Arria V OCT without calibration resistance tolerance to PVT changes.

Symbol	Description	Condition (V)	ResistanceTolerance			Unit
			–I3, –C4	–I5, –C5	–C6	
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 3.0, 2.5	±30	±40	±40	%
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.8, 1.5	±30	±40	±40	%
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.2	±35	±50	±50	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 3.0, 2.5	±30	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8, 1.5	±30	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2	±35	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCIO} = 2.5	±25	±40	±40	%

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max
SSTL-125	1.19	1.25	1.31	0.18	(15)	$V_{CCIO}/2 - 0.15$	$V_{CCIO}/2$	$V_{CCIO}/2 + 0.15$	$2(V_{IH(AC)} - V_{REF})$	$2(V_{IL(AC)} - V_{REF})$

Differential HSTL and HSUL I/O Standards

Table 1-18: Differential HSTL and HSUL I/O Standards for Arria V Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I, II	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	$V_{CCIO} + 0.3$	—	$0.5 \times V_{CCIO}$	—	$0.4 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.6 \times V_{CCIO}$	0.3	$V_{CCIO} + 0.48$
HSUL-12	1.14	1.2	1.3	0.26	0.26	$0.5 \times V_{CCIO} - 0.12$	$0.5 \times V_{CCIO}$	$0.5 \times V_{CCIO} + 0.12$	$0.4 \times V_{CCIO}$	$0.5 \times V_{CCIO}$	$0.6 \times V_{CCIO}$	0.44	0.44

Differential I/O Standard Specifications

Table 1-19: Differential I/O Standard Specifications for Arria V Devices

Differential inputs are powered by V_{CCPD} which requires 2.5 V.

Symbol/Description	Condition	Transceiver Speed Grade 4			Transceiver Speed Grade 6			Unit
		Min	Typ	Max	Min	Typ	Max	
Inter-transceiver block transmitter channel-to-channel skew[39]	×*N* PMA bonded mode	—	—	500	—	—	500	ps

Table 1-24: CMU PLL Specifications for Arria V GX and SX Devices

Symbol/Description	Transceiver Speed Grade 4		Transceiver Speed Grade 6		Unit
	Min	Max	Min	Max	
Supported data range	611	6553.6	611	3125	Mbps
fPLL supported data range	611	3125	611	3125	Mbps

Table 1-25: Transceiver-FPGA Fabric Interface Specifications for Arria V GX and SX Devices

Symbol/Description	Transceiver Speed Grade 4 and 6		Unit
	Min	Max	
Interface speed (single-width mode)	25	187.5	MHz
Interface speed (double-width mode)	25	163.84	MHz

Related Information

- **CTLE Response at Data Rates > 3.25 Gbps across Supported AC Gain and DC Gain** on page 1-35
- **CTLE Response at Data Rates ≤ 3.25 Gbps across Supported AC Gain and DC Gain** on page 1-36
- **Arria V GT, GX, ST, and SX Device Family Pin Connection Guidelines**
  Provides more information about the power supply connection for different data rates.

[39] This specification is only applicable to channels on one side of the device across two transceiver banks.

Symbol	Condition	–I3, –C4			–I5, –C5			–C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
	SERDES factor J ≥ 8[76][78], LVDS TX with RX DPA	[77]	—	1600	[77]	—	1500	[77]	—	1250	Mbps
	SERDES factor J = 1 to 2, Uses DDR Registers	[77]	—	[79]	[77]	—	[79]	[77]	—	[79]	Mbps
Emulated Differential I/O Standards with Three External Output Resistor Network - f_{HSDR} (data rate)[80]	SERDES factor J = 4 to 10[81]	[77]	—	945	[77]	—	945	[77]	—	945	Mbps
Emulated Differential I/O Standards with One External Output Resistor Network - f_{HSDR} (data rate)[80]	SERDES factor J = 4 to 10[81]	[77]	—	200	[77]	—	200	[77]	—	200	Mbps
$t_{x\ Jitter}$ -True Differential I/O Standards	Total Jitter for Data Rate 600 Mbps – 1.25 Gbps	—	—	160	—	—	160	—	—	160	ps
	Total Jitter for Data Rate < 600 Mbps	—	—	0.1	—	—	0.1	—	—	0.1	UI

(78) The V_{CC} and V_{CCP} must be on a separate power layer and a maximum load of 5 pF for chip-to-chip interface.
(79) The maximum ideal data rate is the SERDES factor (J) x the PLL maximum output frequency (f_{OUT}), provided you can close the design timing and the signal integrity simulation is clean.
(80) You must calculate the leftover timing margin in the receiver by performing link timing closure analysis. You must consider the board skew margin, transmitter channel-to-channel skew, and receiver sampling margin to determine the leftover timing margin.
(81) When using True LVDS RX channels for emulated LVDS TX channel, only serialization factors 1 and 2 are supported.

HPS Clock Performance

Table 1-48: HPS Clock Performance for Arria V Devices

Symbol/Description	–I3	–C4	–C5, –I5	–C6	Unit
mpu_base_clk (microprocessor unit clock)	1050	925	800	700	MHz
main_base_clk (L3/L4 interconnect clock)	400	400	400	350	MHz
h2f_user0_clk	100	100	100	100	MHz
h2f_user1_clk	100	100	100	100	MHz
h2f_user2_clk	200	200	200	160	MHz

HPS PLL Specifications

HPS PLL VCO Frequency Range

Table 1-49: HPS PLL VCO Frequency Range for Arria V Devices

Description	Speed Grade	Minimum	Maximum	Unit
VCO range	–C5, –I5, –C6	320	1,600	MHz
	–C4	320	1,850	MHz
	–I3	320	2,100	MHz

HPS PLL Input Clock Range

The HPS PLL input clock range is 10 – 50 MHz. This clock range applies to both HPS_CLK1 and HPS_CLK2 inputs.

Related Information

Clock Select, Booting and Configuration chapter
Provides more information about the clock range for different values of clock select (CSEL).

HPS PLL Input Jitter

Use the following equation to determine the maximum input jitter (peak-to-peak) the HPS PLLs can tolerate. The divide value (N) is the value programmed into the denominator field of the VCO register for each PLL. The PLL input reference clock is divided by this value. The range of the denominator is 1 to 64.

Maximum input jitter = Input clock period × Divide value (N) × 0.02

Table 1-50: Examples of Maximum Input Jitter

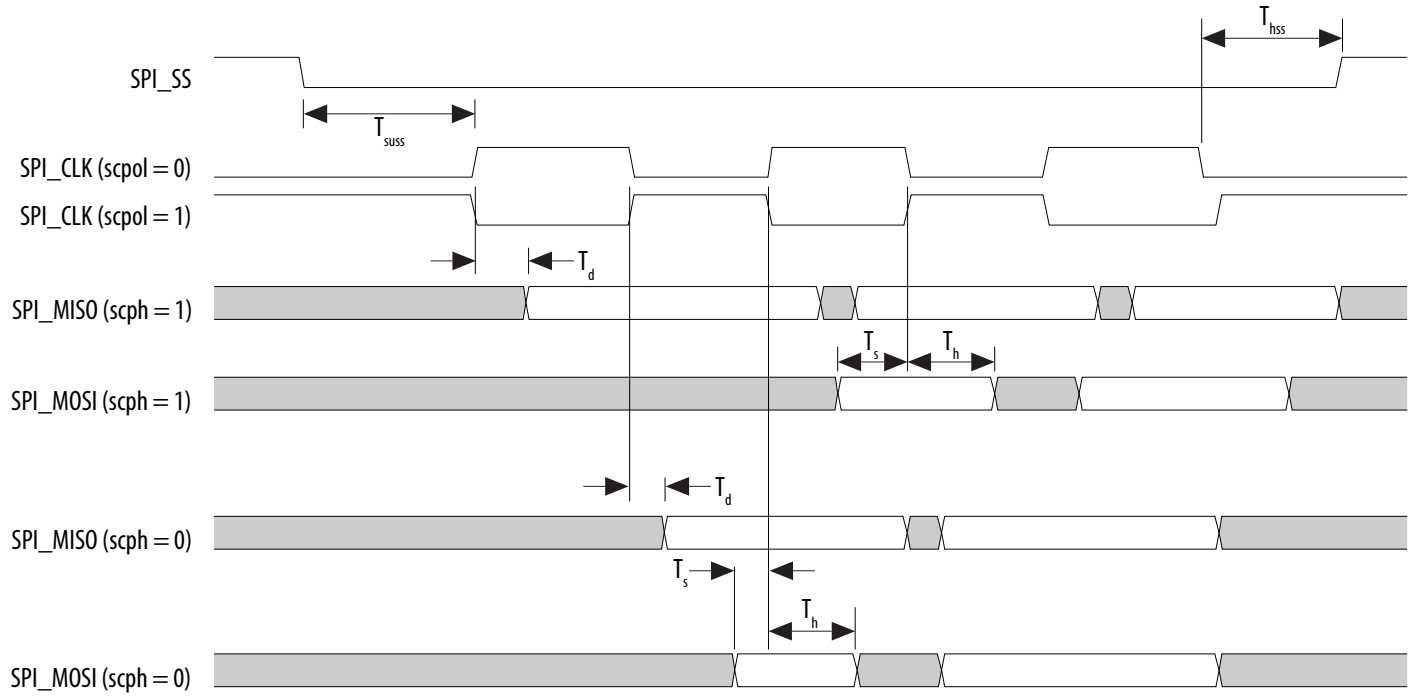
Input Reference Clock Period	Divide Value (N)	Maximum Jitter	Unit
40 ns	1	0.8	ns
40 ns	2	1.6	ns
40 ns	4	3.2	ns

Quad SPI Flash Timing Characteristics

Table 1-51: Quad Serial Peripheral Interface (SPI) Flash Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Max	Unit
F_{clk}	SCLK_OUT clock frequency (External clock)	—	—	108	MHz
T_{qspi_clk}	QSPI_CLK clock period (Internal reference clock)	2.32	—	—	ns
$T_{dutycycle}$	SCLK_OUT duty cycle	45	—	55	%
$T_{dssfrst}$	Output delay QSPI_SS valid before first clock edge	—	1/2 cycle of SCLK_OUT	—	ns
T_{dsslst}	Output delay QSPI_SS valid after last clock edge	–1	—	1	ns
T_{dio}	I/O data output delay	–1	—	1	ns
T_{din_start}	Input data valid start	—	—	$(2 + R_{delay}) \times T_{qspi\_clk} - 7.52$ (85)	ns

Figure 1-10: SPI Slave Timing Diagram



Related Information

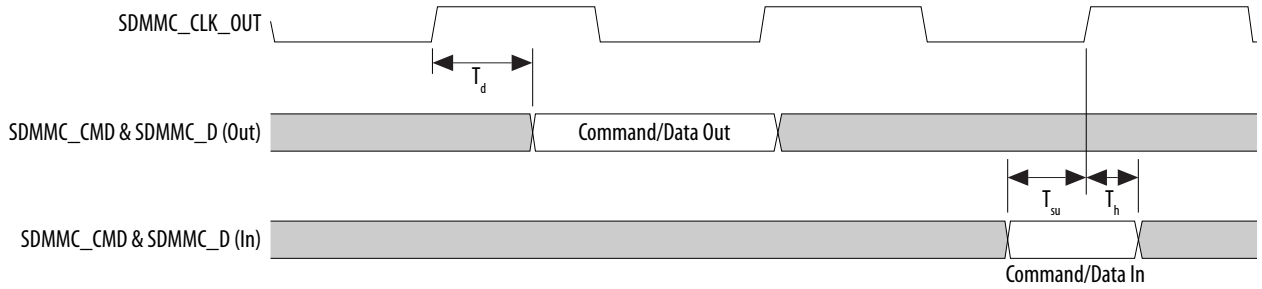
SPI Controller, Arria V Hard Processor System Technical Reference Manual
Provides more information about rx_sample_delay.

SD/MMC Timing Characteristics

Table 1-54: Secure Digital (SD)/MultiMediaCard (MMC) Timing Requirements for Arria V Devices

After power up or cold reset, the Boot ROM uses `drvsel` = 3 and `smplsel` = 0 to execute the code. At the same time, the SD/MMC controller enters the Identification Phase followed by the Data Phase. During this time, the value of interface output clock `SDMMC_CLK_OUT` changes from a maximum of 400 kHz (Identification Phase) up to a maximum of 12.5 MHz (Data Phase), depending on the internal reference clock `SDMMC_CLK` and the `CSEL` setting. The value of `SDMMC_CLK` is based on the external oscillator frequency and has a maximum value of 50 MHz.

Figure 1-11: SD/MMC Timing Diagram



Related Information

Booting and Configuration Chapter, Arria V Hard Processor System Technical Reference Manual
Provides more information about CSEL pin settings in the SD/MMC Controller CSEL Pin Settings table.

USB Timing Characteristics

PHYs that support LPM mode may not function properly with the USB controller due to a timing issue. It is recommended that designers use the MicroChip USB3300 PHY device that has been proven to be successful on the development board.

Table 1-55: USB Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Max	Unit
T_{clk}	USB CLK clock period	—	16.67	—	ns
T_d	CLK to USB_STP/USB_DATA[7:0] output delay	4.4	—	11	ns
T_{su}	Setup time for USB_DIR/USB_NXT/USB_DATA[7:0]	2	—	—	ns
T_h	Hold time for USB_DIR/USB_NXT/USB_DATA[7:0]	1	—	—	ns

Table 1-57: RGMII RX Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Unit
T_{clk} (1000Base-T)	RX_CLK clock period	—	8	ns
T_{clk} (100Base-T)	RX_CLK clock period	—	40	ns
T_{clk} (10Base-T)	RX_CLK clock period	—	400	ns
T_{su}	RX_D/RX_CTL setup time	1	—	ns
T_h	RX_D/RX_CTL hold time	1	—	ns

Figure 1-14: RGMII RX Timing Diagram

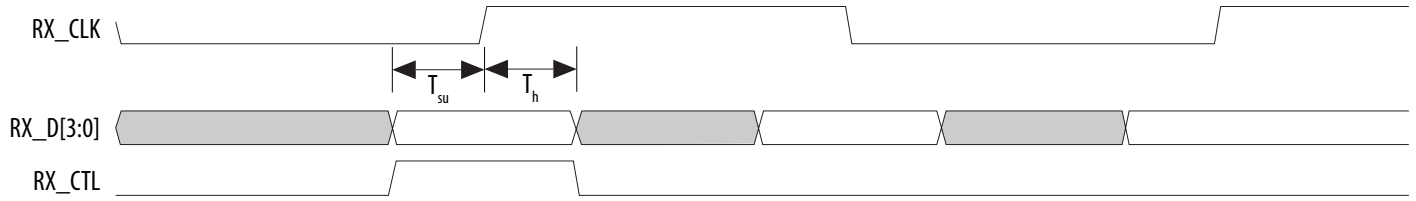


Table 1-58: Management Data Input/Output (MDIO) Timing Requirements for Arria V Devices

Symbol	Description	Min	Typ	Max	Unit
T_{clk}	MDC clock period	—	400	—	ns
T_d	MDC to MDIO output data delay	10	—	20	ns
T_s	Setup time for MDIO data	10	—	—	ns
T_h	Hold time for MDIO data	0	—	—	ns

POR Delay	Minimum	Maximum	Unit
Standard	100	300	ms

Related Information

MSEL Pin Settings
Provides more information about POR delay based on MSEL pin settings for each configuration scheme.

FPGA JTAG Configuration Timing

Table 1-64: FPGA JTAG Timing Parameters and Values for Arria V Devices

Symbol	Description	Min	Max	Unit
t_{JCP}	TCK clock period	30, 167[92]	—	ns
t_{JCH}	TCK clock high time	14	—	ns
t_{JCL}	TCK clock low time	14	—	ns
$t_{JPSU\ (TDI)}$	TDI JTAG port setup time	2	—	ns
$t_{JPSU\ (TMS)}$	TMS JTAG port setup time	3	—	ns
t_{JPH}	JTAG port hold time	5	—	ns
t_{JPCO}	JTAG port clock to output	—	12[93]	ns
t_{JPZX}	JTAG port high impedance to valid output	—	14[93]	ns
t_{JPXZ}	JTAG port valid output to high impedance	—	14[93]	ns

(92) The minimum TCK clock period is 167 ns if V_{CCBAT} is within the range 1.2 V – 1.5 V when you perform the volatile key programming.
(93) A 1-ns adder is required for each VCCIO voltage step down from 3.0 V. For example, tJPCO= 13 ns if VCCIO of the TDO I/O bank = 2.5 V, or 14 ns if it equals 1.8 V.

FPP Configuration Timing when DCLK-to-DATA[] >1

Table 1-67: FPP Timing Parameters When DCLK-to-DATA[] Ratio is >1 for Arria V Devices

Use these timing parameters when you use the decompression and design security features.

Symbol	Parameter	Minimum	Maximum	Unit
t_{CF2CD}	nCONFIG low to CONF_DONE low	—	600	ns
t_{CF2ST0}	nCONFIG low to nSTATUS low	—	600	ns
t_{CFG}	nCONFIG low pulse width	2	—	µs
t_{STATUS}	nSTATUS low pulse width	268	1506(98)	µs
t_{CF2ST1}	nCONFIG high to nSTATUS high	—	1506(99)	µs
t_{CF2CK}(100)	nCONFIG high to first rising edge on DCLK	1506	—	µs
t_{ST2CK}(100)	nSTATUS high to first rising edge of DCLK	2	—	µs
t_{DSU}	DATA[] setup time before rising edge on DCLK	5.5	—	ns
t_{DH}	DATA[] hold time after rising edge on DCLK	$N - 1/f_{DCLK}$(101)	—	s
t_{CH}	DCLK high time	$0.45 \times 1/f_{MAX}$	—	s
t_{CL}	DCLK low time	$0.45 \times 1/f_{MAX}$	—	s
t_{CLK}	DCLK period	$1/f_{MAX}$	—	s
f_{MAX}	DCLK frequency (FPP ×8/ ×16)	—	125	MHz
t_R	Input rise time	—	40	ns
t_F	Input fall time	—	40	ns
t_{CD2UM}	CONF_DONE high to user mode(102)	175	437	µs

(98) This value can be obtained if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
(99) This value can be obtained if you do not delay configuration by externally holding nSTATUS low.
(100) If nSTATUS is monitored, follow the t_{ST2CK} specification. If nSTATUS is not monitored, follow the t_{CF2CK} specification.
(101) N is the DCLK-to-DATA[] ratio and f_{DCLK} is the DCLK frequency of the system.
(102) The minimum and maximum numbers apply only if you chose the internal oscillator as the clock source for initializing the device.

Symbol	Parameter	Minimum	Maximum	Unit
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + (T_{init} × CLKUSR period)	—	—
T_{init}	Number of clock cycles required for device initialization	8,576	—	Cycles

Related Information

FPP Configuration Timing
Provides the FPP configuration timing waveforms.

AS Configuration Timing

Table 1-68: AS Timing Parameters for AS ×1 and ×4 Configurations in Arria V Devices

The minimum and maximum numbers apply to both the internal oscillator and CLKUSR when either one is used as the clock source for device configuration.

The t_{CF2CD}, t_{CF2ST0}, t_{CFG}, t_{STATUS}, and t_{CF2ST1} timing parameters are identical to the timing parameters for passive serial (PS) mode listed in PS Timing Parameters for Arria V Devices table. You can obtain the t_{CF2ST1} value if you do not delay configuration by externally holding nSTATUS low.

Symbol	Parameter	Minimum	Maximum	Unit
t_{CO}	DCLK falling edge to the AS_DATA0/ASDO output	—	2	ns
t_{SU}	Data setup time before the falling edge on DCLK	1.5	—	ns
t_{DH}	Data hold time after the falling edge on DCLK	0	—	ns
t_{CD2UM}	CONF_DONE high to user mode	175	437	µs
t_{CD2CU}	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	—	—
t_{CD2UMC}	CONF_DONE high to user mode with CLKUSR option on	t_{CD2CU} + (T_{init} × CLKUSR period)	—	—
T_{init}	Number of clock cycles required for device initialization	8,576	—	Cycles

Term	Definition
V_{OX}	Output differential cross point voltage
W	High-speed I/O block—Clock boost factor

Document Revision History

Date	Version	Changes

December 2016	2016.12.09	• Updated V_{ICM} (AC coupled) specifications in Receiver Specifications for Arria V GX and SX Devices table.
		• Added maximum specification for T_d in Management Data Input/Output (MDIO) Timing Requirements for Arria V Devices table.
		• Updated T_{init} specifications in the following tables:
		  • FPP Timing Parameters When DCLK-to-DATA[] Ratio is 1 for Arria V Devices
		  • FPP Timing Parameters When DCLK-to-DATA[] Ratio is >1 for Arria V Devices
		  • AS Timing Parameters for AS ×1 and ×4 Configurations in Arria V Devices
		  • PS Timing Parameters for Arria V Devices

June 2016	2016.06.10	• Changed pin capacitance to maximum values.
		• Updated SPI Master Timing Requirements for Arria V Devices table.
		  • Added T_{su} and T_h specifications.
		  • Removed T_{dinmax} specifications.
		• Updated SPI Master Timing Diagram.
		• Updated T_{clk} spec from maximum to minimum in I^2C Timing Requirements for Arria V Devices table.

Symbol	Description	Conditions	Resistance Tolerance		Unit
			C3, I3L	C4, I4	
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
25-Ω R_S	Internal series termination without calibration (25-Ω setting)	V_{CCIO} = 1.2 V	±50	±50	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.8 and 1.5 V	±40	±40	%
50-Ω R_S	Internal series termination without calibration (50-Ω setting)	V_{CCIO} = 1.2 V	±50	±50	%
100-Ω R_D	Internal differential termination (100-Ω setting)	V_{CCIO} = 2.5 V	±25	±25	%

Figure 2-1: OCT Variation Without Re-Calibration for Arria V GZ Devices

$$R_{OCT} = R_{SCAL}\left(1 + \left(\frac{dR}{dT} \times \triangle T\right) \pm \left(\frac{dR}{dV} \times \triangle V\right)\right)$$

Notes:
1. The R_{OCT} value shows the range of OCT resistance with the variation of temperature and V_{CCIO}.
2. R_{SCAL} is the OCT resistance value at power-up.
3. ΔT is the variation of temperature with respect to the temperature at power-up.
4. ΔV is the variation of voltage with respect to the V_{CCIO} at power-up.
5. dR/dT is the percentage change of R_{SCAL} with temperature.
6. dR/dV is the percentage change of R_{SCAL} with voltage.

Table 2-12: OCT Variation after Power-Up Calibration for Arria V GZ Devices

Valid for a V_{CCIO} range of ±5% and a temperature range of 0° to 85°C.

Symbol	Parameter	Min	Typ	Max	Unit
t_{OUTPJ_IO}, (173), (175)	Period Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Period Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
t_{FOUTPJ_IO} (173), (175), (176)	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Period Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
t_{OUTCCJ_IO} (173), (175)	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ($f_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{FOUTCCJ\_IO}$ (173), (175), (176)	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} \geq 100$ MHz)	—	—	600	ps (p-p)
	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ($f_{OUT} < 100$ MHz)	—	—	60	mUI (p-p)
$t_{CASC\_OUTPJ\_DC}$ (173), (177)	Period Jitter for a dedicated clock output in cascaded PLLs ($f_{OUT} \geq 100$ MHz)	—	—	175	ps (p-p)
	Period Jitter for a dedicated clock output in cascaded PLLS ($f_{OUT} < 100$ MHz)	—	—	17.5	mUI (p-p)
dK_{BIT}	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits

(175) The external memory interface clock output jitter specifications use a different measurement method, which is available in the "Memory Output Clock Jitter Specification for Arria V GZ Devices" table.

(176) This specification only covered fractional PLL for low bandwidth. The f_{VCO} for fractional value range 0.05–0.95 must be ≥ 1000 MHz.

(177) The cascaded PLL specification is only applicable with the following condition:
a. Upstream PLL: 0.59Mhz ≤ Upstream PLL BW < 1 MHz
b. Downstream PLL: Downstream PLL BW > 2 MHz

Standard	Training Pattern	Number of Data Transitions in One Repetition of the Training Pattern	Number of Repetitions per 256 Data Transitions (201)	Maximum
Parallel Rapid I/O	00001111	2	128	640 data transitions
	10010000	4	64	640 data transitions
Miscellaneous	10101010	8	32	640 data transitions
	01010101	8	32	640 data transitions

Soft CDR Mode High-Speed I/O Specifications

Table 2-44: High-Speed I/O Specifications for Arria V GZ Devices

When J = 3 to 10, use the serializer/deserializer (SERDES) block.

When J = 1 or 2, bypass the SERDES block.

Symbol	Conditions	C3, I3L			C4, I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Soft-CDR ppm tolerance	—	—	—	300	—	—	300	± ppm

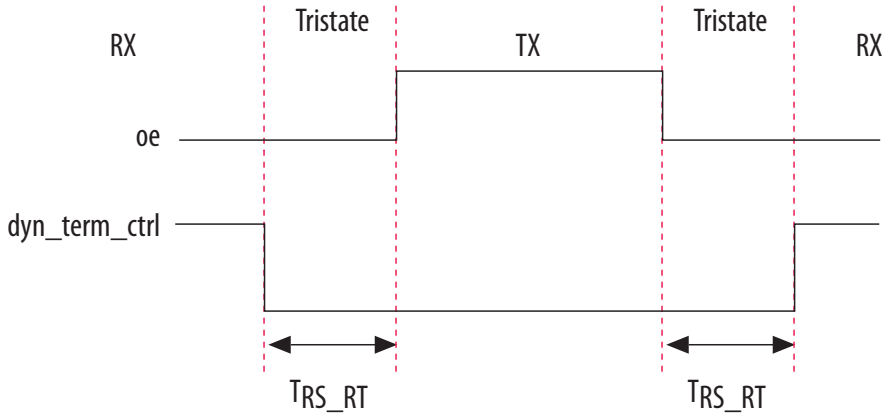
(201) This is the number of repetitions for the stated training pattern to achieve the 256 data transitions.

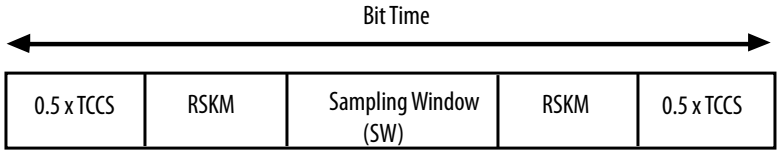
OCT Calibration Block Specifications

Table 2-51: OCT Calibration Block Specifications for Arria V GZ Devices

Symbol	Description	Min	Typ	Max	Unit
OCTUSRCLK	Clock required by the OCT calibration blocks	—	—	20	MHz
T_{OCTCAL}	Number of OCTUSRCLK clock cycles required for OCT R_S/R_T calibration	—	1000	—	Cycles
$T_{OCTSHIFT}$	Number of OCTUSRCLK clock cycles required for the OCT code to shift out	—	32	—	Cycles
T_{RS_RT}	Time required between the `dyn_term_ctrl` and `oe` signal transitions in a bidirectional I/O buffer to dynamically switch between OCT R_S and R_T (See the figure below.)	—	2.5	—	ns

Figure 2-6: Timing Diagram for `oe` and `dyn_term_ctrl` Signals



Term	Definition
R_L	Receiver differential input discrete resistor (external to the Arria V GZ device).
SW (sampling window)	Timing Diagram—the period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window, as shown: 
Single-ended voltage referenced I/O standard	The JEDEC standard for SSTL and HSTL I/O defines both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the DC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: Single-Ended Voltage Referenced I/O Standard